**ELEC 7950-001: VLSI Design & Test Seminar**

**Broun 235, November 2, 2011, 4PM**

**A Unified Program for Modifying Built-In Self-Test Architectures for Xilinx Field Programmable Gate Arrays (Master’s Project Defense)**

**Neil Da Cunha**

A Built-In Self-Test session is created with two programs. The first program, a BIST generation program, creates a template file which is then modified by the second program, a BIST modification program, into the different phases that make up a test session. Currently there are twelve BIST modification programs and a proposal was made to combine them into one program. This presentation will discuss the motivations and results of combining the functionality of the BIST generation programs into a single program.

Contact for seminar and course:

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